

The Next Chapter for the *Journal of Forensic Sciences*

It is always sad when a long relationship ends. For the past 35 years ASTM, now ASTM International, has published the *Journal of Forensic Sciences (JFS)*. Over this period, Abel Dominguez, Bob Gaensslen and myself have served as Editors of *JFS* and relied upon the wonderful staff of ASTM to help us. On behalf of the American Academy of Forensic Sciences (AAFS) and the past and present Editors, I thank ASTM and all those in that organization who have been instrumental in making *JFS* what it is today—the leading forensic science journal in the world. In particular I would like to thank the following as they have been of valuable assistance to the present Editorial Office:

Therese Blyler
Robert Dreyfuss
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Kathe Hooper
Margaret Lawlor
Robert Meltzer
Roberta Storer

Beginning in January 2006, Blackwell Publishing, Inc. will publish *JFS*. From the reader's viewpoint there will be no change—you will receive the Journal every two months and have access to web-based papers through the AAFS website, or if a non-member through

www.blackwellpublishing.com. *JFS* will look the same and contain the same high-quality papers that you are accustomed to reading.

But change does produce change. For example, we will begin web-based manuscript submission and peer-review in January 2006. More information on this process will be available at www.aafs.org, and included in the AAFS Newsletter, in late 2005. After several meetings with the Blackwell staff and the Academy Office, I am very confident that this will be a transparent transition, but if you do experience any inconvenience, please contact Blackwell (at 781 388 8206 or subscrip@blackwellpublishing.com), the Academy Office (at 719 636 1100 or www.aafs.org), or myself (at 281 419 6236 or JFS.editor@att.net).

For those subscribers who are not members of AAFS, I would suggest that you contact Blackwell to verify that your subscription will continue without interruption. You are an important part of our readership and I certainly want to insure that you continue to be a subscriber.

Change is exciting and *JFS* is growing. ASTM International has worked closely with us for over thirty years and has made numerous contributions to the Journal that has helped in our success. Thank you ASTM for all the effort, hard work, dedication, and imagination that you have brought to *JFS*.

Michael A. Peat, Ph.D.
Editor, *JFS*